## Applicant(s)/Patent Under Application/Control No. Reexamination 10/765,954 HWANG ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2627 TAN X. DINH **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2005/0002294 A1 01-2005 Hwang et al. 369/47.14 Α US-В С US-D US-US-Ε US-F US-G US-Н US-US-J US-Κ US-US-**FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s T

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